

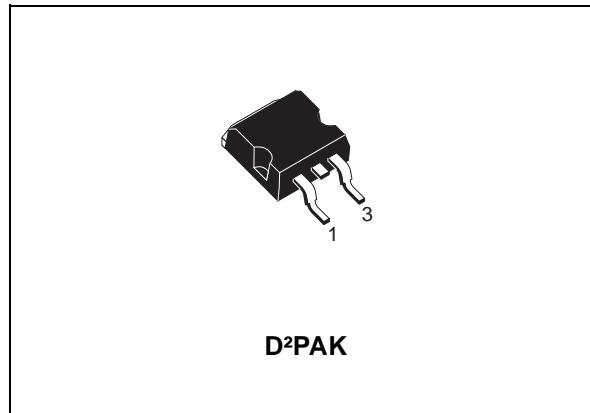


# STGB20NB37LZ

## N-CHANNEL CLAMPED 20A - D<sup>2</sup>PAK INTERNALLY CLAMPED PowerMESH™ IGBT

TYPE	V <sub>CES</sub>	V <sub>CE(sat)</sub>	I <sub>C</sub>
STGB20NB37LZ	CLAMPED	< 2.0 V	20 A

- POLYSILICON GATE VOLTAGE DRIVEN
- LOW THRESHOLD VOLTAGE
- LOW ON-VOLTAGE DROP
- LOW GATE CHARGE
- HIGH CURRENT CAPABILITY
- HIGH VOLTAGE CLAMPING FEATURE
- ADD SUFFIX "T4" FOR ORDERING IN TAPE & REEL

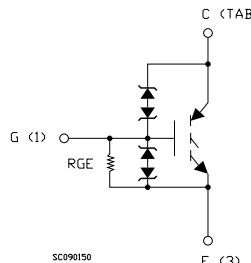


D<sup>2</sup>PAK

### DESCRIPTION

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The built in collector-gate zener exhibits a very precise active clamping while the gate-emitter zener supplies an ESD protection.

### INTERNAL SCHEMATIC DIAGRAM



### APPLICATIONS

- AUTOMOTIVE IGNITION

### ORDERING INFORMATION

SALES TYPE	MARKING	PACKAGE	PACKAGING
STGB20NB37LZT4	GB20NB37LZ	D <sup>2</sup> PAK	TAPE & REEL

## STGB20NB37LZ

### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-Emitter Voltage ( $V_{GS} = 0$ )	CLAMPED	V
$V_{ECR}$	Emitter-Collector Voltage	20	V
$V_{GE}$	Gate-Emitter Voltage	CLAMPED	V
$I_C$	Collector Current (continuos) at $T_C = 25^\circ C$	40	A
$I_C$	Collector Current (continuos) at $T_C = 100^\circ C$	20	A
$I_{CM} (\bullet)$	Collector Current (pulsed)	80	A
$E_{as}$	Single Pulse Energy $T_C = 25^\circ C$	700	mJ
$P_{TOT}$	Total Dissipation at $T_C = 25^\circ C$	200	W
	Derating Factor	1.33	W/ $^\circ C$
$E_{SD}$	ESD (Human Body Model)	8	kV
$T_{stg}$	Storage Temperature	-55 to 175	$^\circ C$
$T_j$	Max. Operating Junction Temperature		

( $\bullet$ ) Pulse width limited by safe operating area

### THERMAL DATA

R <sub>thj-case</sub>	Thermal Resistance Junction-case Max	0.75	$^\circ C/W$
R <sub>thj-amb</sub>	Thermal Resistance Junction-ambient Max	62.5	$^\circ C/W$

### ELECTRICAL CHARACTERISTICS (T<sub>CASE</sub> = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV <sub>(CES)</sub>	Clamped Voltage	$I_C = 2 \text{ mA}, V_{GE} = 0, T_C = -40^\circ C$	375	405	425	V
		$I_C = 2 \text{ mA}, V_{GE} = 0, T_C = 25^\circ C$		400		V
		$I_C = 2 \text{ mA}, V_{GE} = 0, T_C = 150^\circ C$		395		V
BV <sub>(ECR)</sub>	Emitter Collector Break-down Voltage	$I_C = 75 \text{ mA}, T_C = 25^\circ C$	20	28		V
BV <sub>GE</sub>	Gate Emitter Break-down Voltage	$I_G = \pm 2 \text{ mA}$	12	14	16	V
I <sub>CES</sub>	Collector cut-off Current ( $V_{GE} = 0$ )	$V_{CE} = 15 \text{ V}, V_{GE} = 0, T_C = 150^\circ C$			10	$\mu A$
		$V_{CE} = 200 \text{ V}, V_{GE} = 0, T_C = 150^\circ C$			100	$\mu A$
I <sub>GES</sub>	Gate-Emitter Leakage Current ( $V_{CE} = 0$ )	$V_{GE} = \pm 10 \text{ V}, V_{CE} = 0$	$\pm 300$	$\pm 660$	$\pm 1000$	$\mu A$
R <sub>GE</sub>	Gate Emitter Resistance		10	15	30	$K\Omega$

### ON (\*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>GE(th)</sub>	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_C = 250 \mu A, T_C = -40^\circ C$	1.2			V
		$V_{CE} = V_{GE}, I_C = 250 \mu A, T_C = 25^\circ C$	1	1.4	2	V
		$V_{CE} = V_{GE}, I_C = 250 \mu A, T_C = 150^\circ C$	0.6			V
V <sub>CE(SAT)</sub>	Collector-Emitter Saturation Voltage	$V_{CE} = 4.5 \text{ V}, I_C = 10 \text{ A}, T_C = 25^\circ C$		1.1	1.8	V
		$V_{CE} = 4.5 \text{ V}, I_C = 10 \text{ A}, T_C = 150^\circ C$		1.0	1.7	V
		$V_{CE} = 4.5 \text{ V}, I_C = 20 \text{ A}, T_C = 25^\circ C$		1.35	2.0	V
		$V_{CE} = 4.5 \text{ V}, I_C = 20 \text{ A}, T_C = 150^\circ C$		1.25	2.0	V

## DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs}$ (1)	Forward Transconductance	$V_{CE} = 25 \text{ V}$ , $I_C = 20 \text{ A}$		35		S
$C_{ies}$	Input Capacitance	$V_{CE} = 25 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GE} = 0$		2300		pF
$C_{oes}$	Output Capacitance			165		pF
$C_{res}$	Reverse Transfer Capacitance			28		pF
$Q_g$	Gate Charge	$V_{CE} = 280 \text{ V}$ , $I_C = 20 \text{ A}$ , $V_{GE} = 5 \text{ V}$		51		nC

## FUNCTIONAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_l$	Latching Current	$V_{Clamp} = 250 \text{ V}$ , $T_C = 125^\circ\text{C}$ $R_{GOFF} = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$		40		A
U.I.S.	Functional Test Open Secondary Coil	$R_{GOFF} = 1\text{K}\Omega$ , $L = 1.6 \text{ mH}$ , $T_C = 125^\circ\text{C}$		20		A

## SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on Delay Time	$V_{CC} = 250 \text{ V}$ , $I_C = 20 \text{ A}$		2.3		$\mu\text{s}$
$t_r$	Rise Time	$R_G = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$		0.6		$\mu\text{s}$
$(di/dt)_{on}$	Turn-on Current Slope	$V_{CC} = 250 \text{ V}$ , $I_C = 20 \text{ A}$ $R_G = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$		550		$\text{A}/\mu\text{s}$
$E_{on}$	Turn-on Switching Losses	$V_{CC} = 250 \text{ V}$ , $I_C = 20 \text{ A}$ , $T_C = 25^\circ\text{C}$ $R_G = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$ , $T_C = 150^\circ\text{C}$		8.8		$\text{mJ}$
				9.2		$\text{mJ}$

## SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_c$	Cross-over Time	$V_{CC} = 250 \text{ V}$ , $I_C = 20 \text{ A}$ ,		4.8		$\mu\text{s}$
$t_r(V_{off})$	Off Voltage Rise Time	$R_{GE} = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$		2.6		$\mu\text{s}$
$t_d(off)$	Delay Time			2.0		$\mu\text{s}$
$t_f$	Fall Time			11.5		$\mu\text{s}$
$E_{off}^{(**)}$	Turn-off Switching Loss			11.8		$\text{mJ}$
$t_c$	Cross-over Time	$V_{CC} = 250 \text{ V}$ , $I_C = 20 \text{ A}$ ,		7.8		$\mu\text{s}$
$t_r(V_{off})$	Off Voltage Rise Time	$R_{GE} = 1\text{K}\Omega$ , $V_{GE} = 4.5 \text{ V}$		3.5		$\mu\text{s}$
$t_d(off)$	Delay Time	$T_j = 125^\circ\text{C}$		3.9		$\mu\text{s}$
$t_f$	Fall Time			12.0		$\mu\text{s}$
$E_{off}^{(**)}$	Turn-off Switching Loss			17.8		$\text{mJ}$

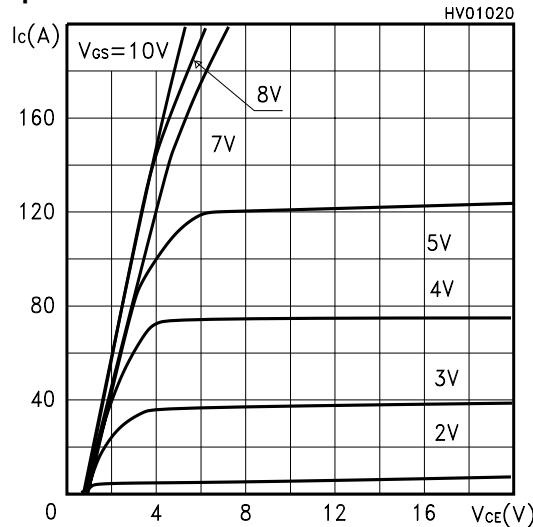
(1)Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5 %.

(\*)Pulse width limited by max. junction temperature.

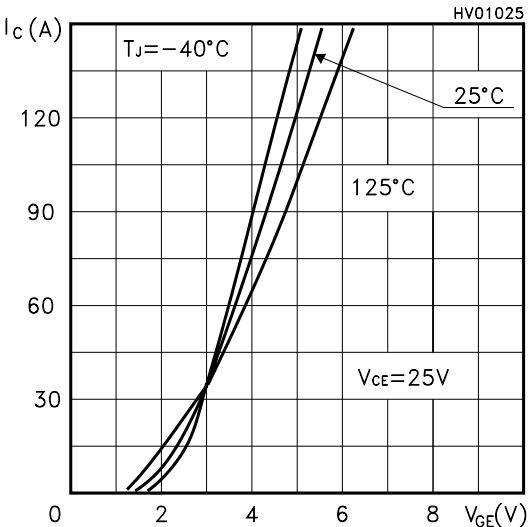
(\*\*)Losses Include Also the Tail

## STGB20NB37LZ

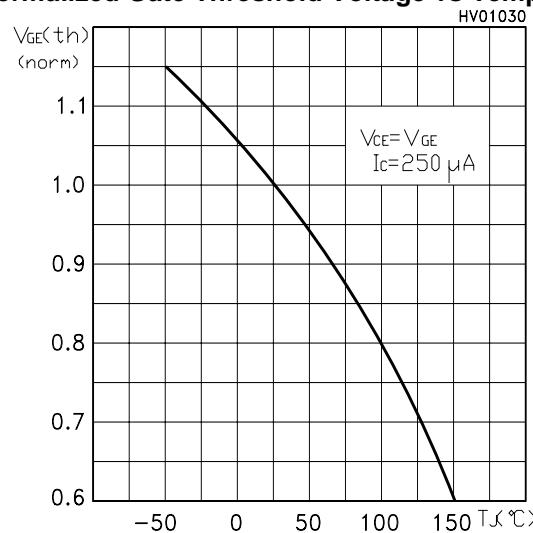
### Output Characteristics



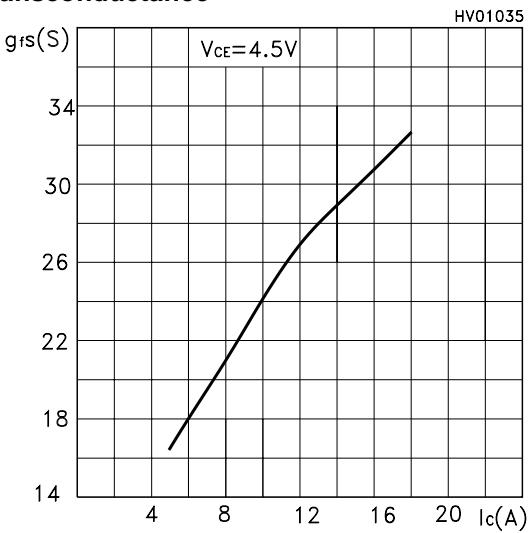
### Transfer Characteristics



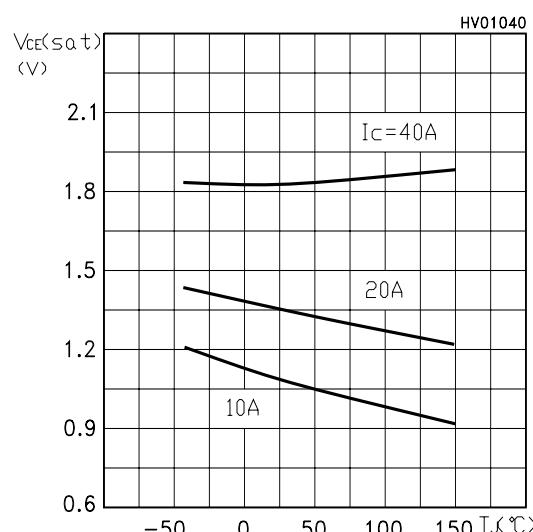
### Normalized Gate Threshold Voltage vs Temp.



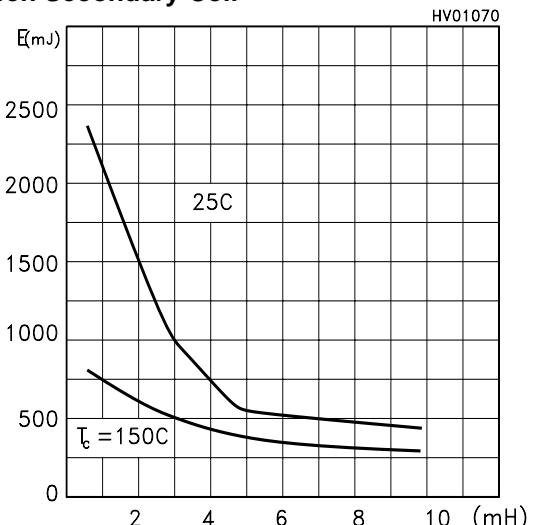
### Transconductance



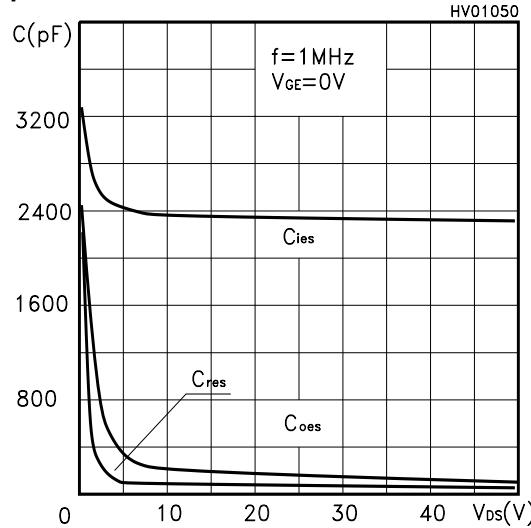
### Collector-Emitter On Voltage vs Temperature



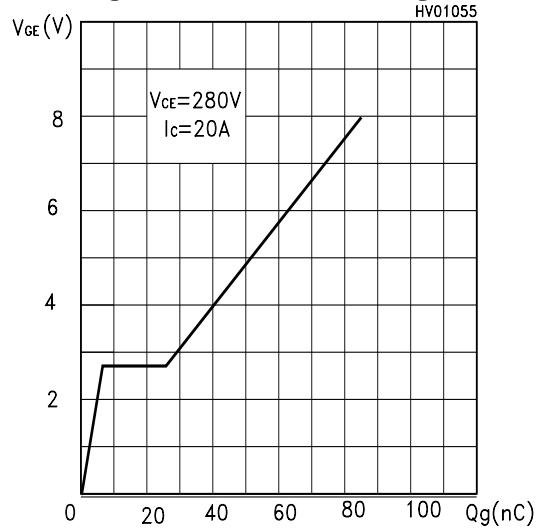
### Self Clamped Inductive Switching Energy vs Open Secondary Coil



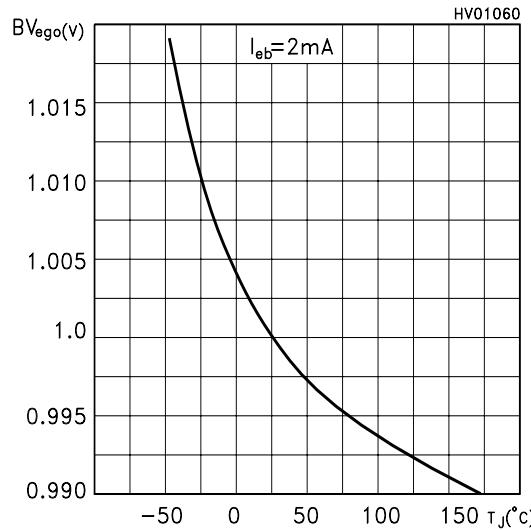
**Capacitance Variations**



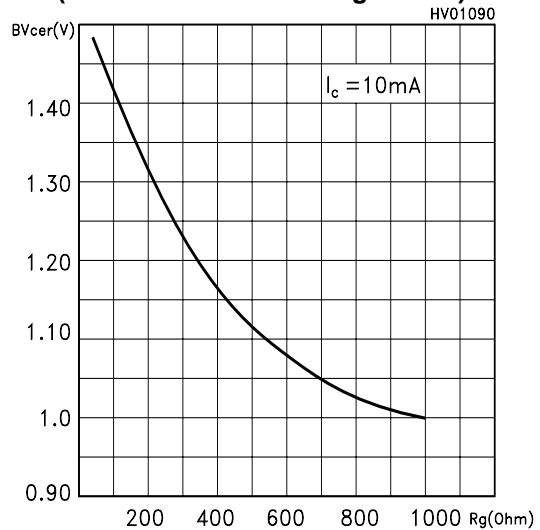
**Gate Charge vs Gate-Emitter Voltage**



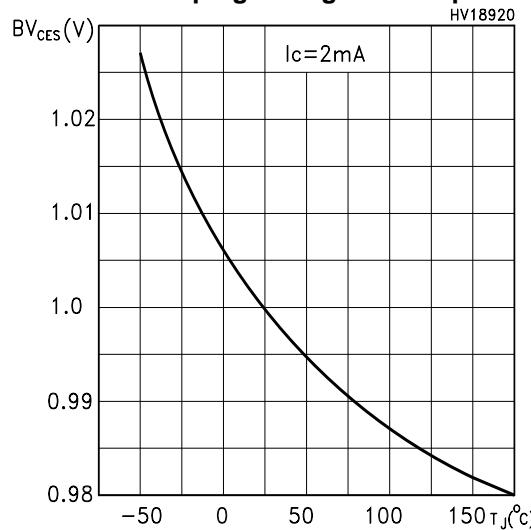
**Normalized  $BV_{GEO}$  (Zener Gate-Emitter) vs Temperature**



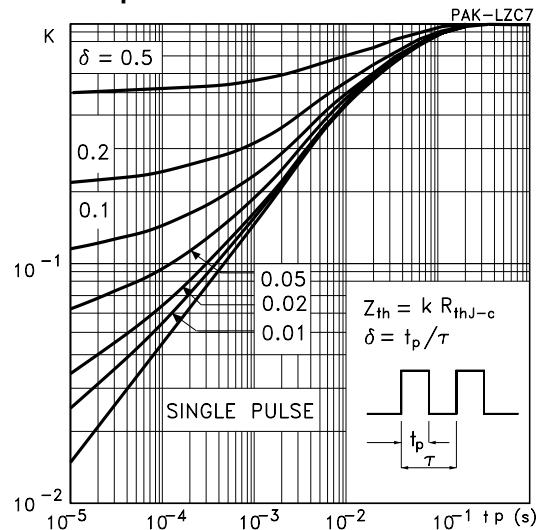
**Normalized Clamping Voltage vs Gate Resistance (Inductive Switch Configuration)**



**Normalized Clamping Voltage vs Temperature**

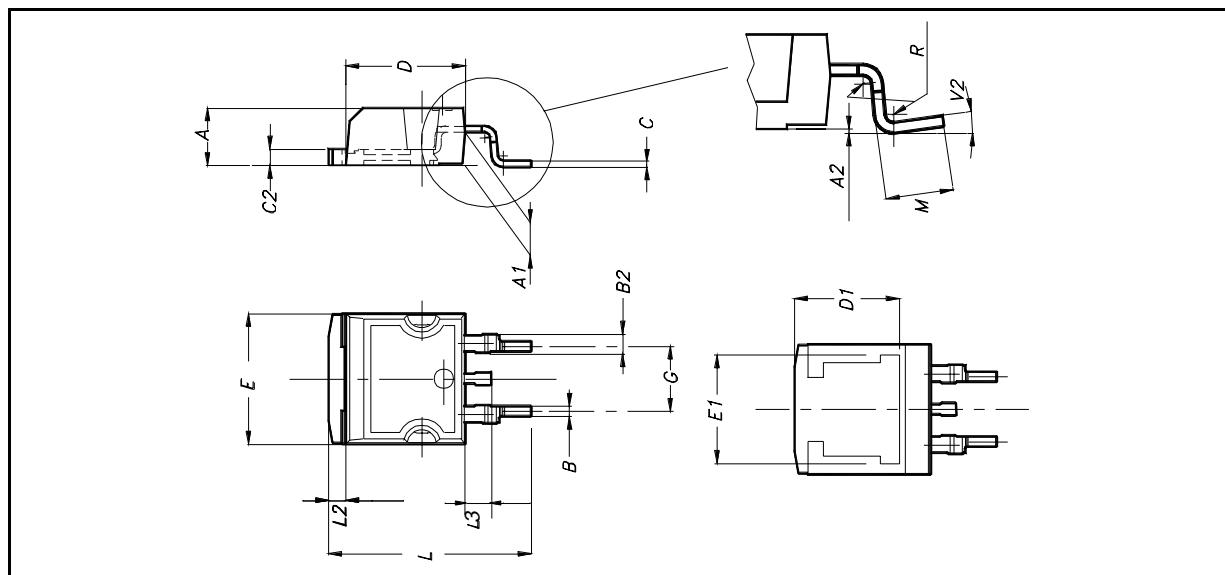


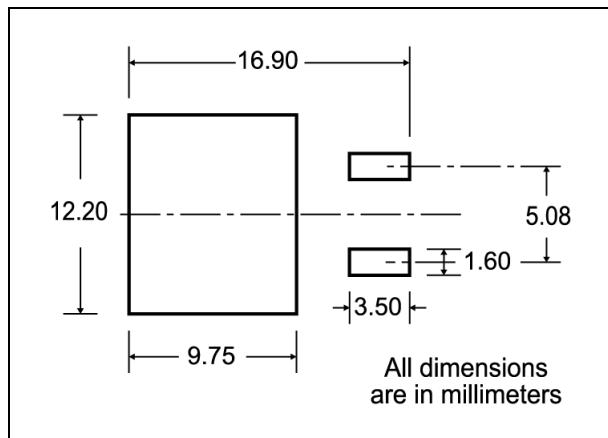
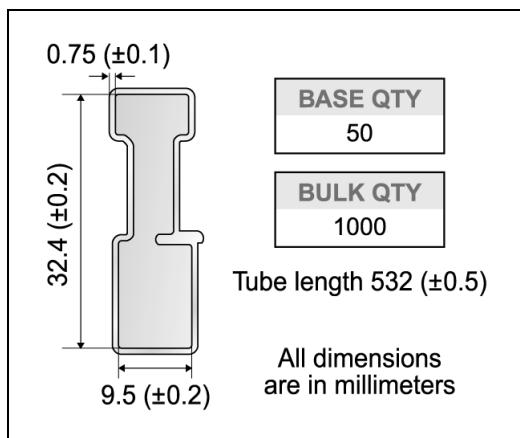
**Thermal Impedance**



D<sup>2</sup>PAK MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
B	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
C	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
M	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	0°		8°			



**D<sup>2</sup>PAK FOOTPRINT****TUBE SHIPMENT (no suffix)\*****TAPE AND REEL SHIPMENT (suffix "T4")\***

**TAPE MECHANICAL DATA**

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A0	10.5	10.7	0.413	0.421
B0	15.7	15.9	0.618	0.626
D	1.5	1.6	0.059	0.063
D1	1.59	1.61	0.062	0.063
E	1.65	1.85	0.065	0.073
F	11.4	11.6	0.449	0.456
K0	4.8	5.0	0.189	0.197
P0	3.9	4.1	0.153	0.161
P1	11.9	12.1	0.468	0.476
P2	1.9	2.1	0.075	0.082
R	50		1.574	
T	0.25	0.35	0.0098	0.0137
W	23.7	24.3	0.933	0.956

**REEL MECHANICAL DATA**

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A			330	12.992
B	1.5		0.059	
C	12.8	13.2	0.504	0.520
D	20.2		0795	
G	24.4	26.4	0.960	1.039
N	100		3.937	
T			30.4	1.197

<b>BASE QTY</b>	<b>BULK QTY</b>
1000	1000

10 pitches cumulative tolerance on tape  $+/- 0.2$  mm

Center line of cavity

User Direction of Feed

TRL

FEED DIRECTION →

Bending radius R min.

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